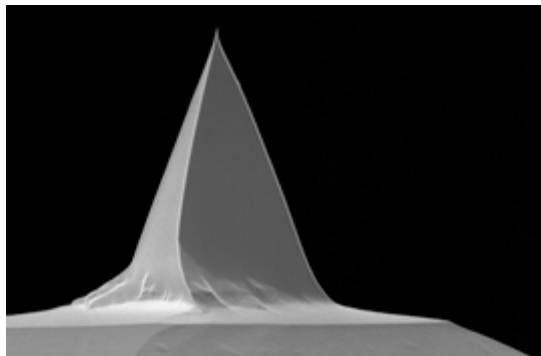


# ANSCM-PA

ANSCM-PA probes are non-contact / tapping mode probes designed for Electronic Force Microscopy applications. These probes are coated on the reflex and tip sides with a thin layer of Pt-Ir, which allows for high resolution imaging.

## Tip Specifications

- **Material:** Silicon
- **Shape:** Pyramidal
- **Height ( $\mu\text{m}$ ):** 14-16
- **Aspect ratio:** 1.5-3.0
- **ROC (nm) :** 30
- **Coating:** Pt/Ir, 25 nm  $\pm$  5



[ANSCM-PA](#)

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## Cantilever Specifications

Material: Silicon

Shape : Rectangular

Reflex coating : Pt/Ir, 25 nm  $\pm$  5

Parameter	Nominal	Min	Max
k (N/m)	40	25	75
f (kHz)	300.0	200.0	400.0
Length ( $\mu\text{m}$ )	125.0	115.0	135.0
Width ( $\mu\text{m}$ )	35.0	30.0	40.0
Thickness ( $\mu\text{m}$ )	4.50	4.00	5.00